





#### ISO/IEC17025 Accredited Lab.

EMC 1503061

File reference No: 2015-03-10

Applicant:

JEOLY ELECTRONICS&STATIONERY CO.,LTD.

Product:

Electronic Clock

Brand Name:

N/A

Model No:

CM-192, CM-220, CM-222, CG-503

Test Standards:

EN 55022: 2010+AC:2011

EN61000-3-2:2006+A1:2009+A2:2009

EN 55024: 2010 EN 61000-3-3: 2013

Test result:

The EMC testing has been performed on the submitted samples

and found in compliance with council EMC Directive

2004/108/EC.

Approved By

Terry Tang

Manager

Dated:

March 10, 2015

Results appearing herein relate only to the sample tested The technical reports is issued errors and omissions exempt and is subject to withdrawal at

#### SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519, 5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen, Guangdong China

Tel (755) 83448688

Fax (755) 83442996

Email: info@timewaytech.com

Report No: EMC1503061 Page 2 of 52

Date: 2015-03-10



# **Special Statement:**

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

The testing quality system of our laboratory meets with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

#### **CNAS-LAB Code: L2292**

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of testing Laboratories.

## FCC-Registration No.: 899988

The EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications commission. The acceptance letter from the FCC is maintained in our files. Registration No.:899988.

# IC- Registration No.: IC5205A-02

The EMC Laboratory has been registered and fully described in a report filed with the (IC) Industry Canada. The acceptance letter from the IC is maintained in our files. Registration No.: IC 5205A-02.

Date: 2015-03-10



# TABLE OF CONTENT

1.0	Ger	neral Details	5
	1.1	Test Lab Details	5
	1.2	Applicant Details	5
	1.3	Description of EUT	5
	1.4	Submitted Sample(s)	5
	1.5	Test Duration	5
	1.6	Additional information of EUT	6
	1.7	Test Engineer	6
2.0	List	t of Measurement Equipment	7
	2.1	Conducted Emission Test.	7
	2.2	Radiated Disturbance Test	7
	2.3	Harmonic & Flicker Test	7
	2.4	ESD Test	7
	2.5	RF field Strength Susceptibility	8
	2.6	Electrical Fast Transient/Burst (EFT/B) Immunity test	8
	2.7	Surge Test	8
	2.8	Conducted Immunity Test	8
	2.9	Power-frequency Magnetic Field	8
	2.10	Voltage Dips/Interruption Immunity Test	9
3.0	Tec	chnical Details	
	3.1	Investigations Requested	10
	3.2	Test Standards	10
	3.3	Performance Criteria	10
	3.4	Test standards and Results Summary Tables	11
4.0	Ele	ctromagnetic Interference Test results	12
	4.1	Power line Conducted Emission Test	
	4.2	Telecommunication ports Conducted Emission Test	15
	4.3	Radiated Disturbance Test	18
	4.4	Harmonic Current Emission Test.	27
	4.5	Voltage Fluctuations &Flicker Test.	29
5.0	Imr	munity Test	31
	5.1	Electrostatic Discharge	31
	5.2	RF field strength susceptibility (80MHz 1000MHz)	33
	5.3	Electrical Fast Transient/Burst (EFT/B) immunity test	
	5.4	Surge test	
	5.5	Conducted Immunity test	39
	5.6	Power-Frequency magnetic field test.	41

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any

discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES, reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Page 4 of 52

Report No: EMC1503061

Date: 2015-03-10



	5.7	Voltage Dips/Interruptions immunity test	43
<b>6.0</b> ]	Produ	ıct Labelling	45
		CE Mark label specification	
		Mark Location: Rear enclosure	
7.0	Pho	oto of testing	46

Date: 2015-03-10



#### 1.0 General Details

#### 1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519,5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen,

Guangdong China

Tel(086) 755-83448688 Fax (086) 755-83442996

#### **Test Location**

#### All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519,5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen,

Guangdong China

Tel(086) 755-83448688 Fax (086) 755-83442996

No tests were sub-contracted.

#### 1.2 Applicant Details

Applicant: JEOLY ELECTRONICS&STATIONERY CO.,LTD.

Address: SHIWAN IND.ZONE, YONG-SHI ROAD, SHIWAN TOWN, BOLUO COUNTY,

HUIZHOU CITY, GUANGDONG PROVINCE, CHINA

Telephone: 0755-28365284

Fax:

Manufacturer: JEOLY ELECTRONICS&STATIONERY CO., LTD.

Address: SHIWAN IND.ZONE, YONG-SHI ROAD, SHIWAN TOWN, BOLUO COUNTY,

HUIZHOU CITY, GUANGDONG PROVINCE, CHINA

Telephone: -Fax: --

#### 1.3 Description of EUT

Product: Electronic Clock

Brand Name: N/A Model Number: CM-192

Adding Model Number: CM-220, CM-222, CG-503

Rating: Input: DC1.5V;

#### 1.4 Submitted Sample(s)

4 Sample

#### 1.5 Test Duration

2015-03-07 to 2015-03-09

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Page 6 of 52

Report No: EMC1503061

Date: 2015-03-10



#### 1.6 Additional information of EUT

	Submitted	Not Available
User Manual	$\boxtimes$	
Part List		
Circuit Diagram	$\boxtimes$	
Printed circuit board[PCB] Layout	$\boxtimes$	
Block Diagram		

1.7 Test Engineer

The sample(s) tested by

Print Name: Leo Lau/Engineer

This test report is not valid without personnel's signatures of SHENZHEN TIMEWAY TESTING LABORATORIES

discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES, reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 7 of 52

Date: 2015-03-10



#### 2.0 List of Measurement Equipment

#### Conducted Emission Test 2.1

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESH3	860905/006	RS	2014.06.24	1Year
Spectrum Analyzer	ESA-L1500A	US37451154	HP	2014.06.24	1Year
PULSE LIMITER	ESH3-Z2	100281	RS	2014.06.24	1Year
LISN	ESH3-Z5	100294	RS	2014.06.24	1Year
LISN	ESH3-Z5	100253	RS	2014.06.24	1Year

#### 2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESVD	100008	RS	2014.06.24	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
Spectrum Analyzer	8595E	3441A00893	HP	2014.06.24	1Year
Amplifier	8447D	2727A05017	HP	2014.06.24	1Year
Bilog Antenna	VULB9163	9163/340	Schwarebeck	2014.06.24	1Year

#### 2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test System	PACS-1	72305	CI	2014.06.24	1Year
5K VA AC Power Source	5001iX	56060	CI	2014.06.24	N/A

#### 2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	DITO	0404-24	EM TEST	2014.05.29	1Year

Date: 2015-03-10



## 2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2014.06.24	1Year
Power Meter	NRVS		RS	2014.06.24	1Year
Voltage Probe	URV5-Z2	100012	RS	2014.06.24	1Year
Voltage Probe	URV5-Z2	100013	RS	2014.06.24	1Year
Power Amplifier	150W1000	300999	AR	2014.06.24	1Year
Power Amplifier	25S1G4AM1	305993	AR	2014.06.24	1Year
Field Probe	CBL6111C	2576	Holaday	2014.06.24	1Year
Bilog Antenna	MCDC		Chase	2014.06.24	1Year

## 2.6 Electrical Fast Transient/Burst (EFT/B) Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2014.06.24	1Year
Power Source	MV2616	0104-14	EM TEST	2014.07.24	1Year

# 2.7 Surge Test

Name	Model No.	Serial No.	Manufacturer	Calibration Date	Calibration Cycle
Ultra Compact	UCS 500			2014.06.24	
Simulator	M4	0304-42	EM TEST		1Year
Power Source	MV2616	0104-14	EM TEST	2014.07.24	1Year

# 2.8 Conducted Immunity Test

					Calibration	Calibration
Name		Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous	Wave					
Simulator		CWS 500C	0407-05	EM TEST	2014.06.26	1 Year

# 2.9 Power-frequency Magnetic Field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wav	UCS 500 M4	0204 42		2014.06.24	
Simulator	UCS 300 MI4	0304-42	EM TEST		1 Year
Power Source NV 2016		0104-14		2014.07.24	
Network	MV 2616	0104-14	EM TEST		1 Year
Current Transformer	MC2630		EM TEST	2014.06.24	1 Year

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to

adopt any other remedies which may be appropriate.

Page 9 of 52 Report No: EMC1503061

Date: 2015-03-10



Magnetic Coil MS10	0 0304-42	EM TEST	2014.06.24	1 Year
--------------------	-----------	---------	------------	--------

# Voltage Dips/Interruption Immunity Test

<u> </u>	1	J			
				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact				2014.06.24	
Simulator	UCS 500 M4	0304-42	EM TEST		1Year
Power Source	MV2616	0104-14	EM TEST	2014.07.24	1Year

Report No: EMC1503061 Page 10 of 52

Date: 2015-03-10



# 3.0 Technical Details

#### 3.1 Investigations Requested

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility [EMS] tests for CE Marking

#### 3.2 Test Standards

	Test Standards	_		
EN 55022: 2010+AC:2011	Limits and methods of measuremen	nt of radio disturbance characteristics of		
EN 33022. 2010+AC.2011				
EN61000-3-2:2006+A1:2009	Electromagnetic compatibility(EMC)- Part 3-2:Limits-Limits for harmonic			
+A2:2009	current emissions(equipment input current ≤16A per phase)			
	Electromagnetic compatibility (EMC	C)- Part 3-3:Limits-Limitation of voltage		
EN 61000-3-3:2013	changes, Voltage fluctuations and	flicker in public low-voltage supply		
EN 01000-3-3.2013	systems. For equipment with rated current ≤16A per phase and not subject			
	to conditional connection			
EN 55024:2010	Information technology equipment — Immunity characteristics — Limits and			
EN 33024.2010	methods of measurement			
	EN 61000-4-2:2009	Electrostatic discharge		
	EN 61000-4-3:2006	RF field strength susceptibility		
	EN 61000-4-4:2004+A1:2010	Electrical Fast transients		
	EN 61000-4-5:2006	Surge		
	EN 61000-4-6:2009	Conducted susceptibility		
	EN 61000-4-8:2010	Power-frequency Magnetic Field		
	EN 61000-4-11:2004	Dips/Voltage Interruption Variation		

## 3.3 Performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Page 11 of 52

Report No: EMC1503061

Date: 2015-03-10



#### Test standards and Results Summary Tables

Test Condition	Test Requirement	Test Method	Test Result	
	EMISSION Results Sumi	mary		
Conducted Emission on AC Mains,	EN 55022: 2010+AC:2011	EN 55022: 2010+AC:2011	N/A	
150KHz to 30MHz			IN/A	
Conducted Emission on at	EN 55022: 2010+AC:2011	EN 55022: 2010+AC:2011		
telecommunication ports,			N/A	
150KHz to 30MHz				
Radiated Emissions,	EN 55022: 2010+AC:2011	EN 55022: 2010+AC:2011	D	
30MHz to 1GHz			Pass	
Harmonic Emissions on AC supply	EN61000-3-2:2006+A1:2009	EN61000-3-2:2006+A1:2009	NT/A	
	+A2:2009	+A2:2009	N/A	
Voltage fluctuations on AC supply	EN 61000-3-3: 2013	EN 61000-3-3: 2013	N/A	
	IMMUNITY Results Sum	mary		
Electrostatic Discharge	EN 55024: 2010	EN 61000-4-2: 2009	Pass	
Electrical Fast transients	EN 55024: 2010	EN 61000-4-4: 2004+A1:2010	NT/A	
/Burst Immunity			N/A	
RF field strength susceptibility	EN 55024: 2010	EN 61000-4-3: 2006	Pass	
Surge	EN 55024: 2010	EN 61000-4-5: 2006	N/A	
Conducted susceptibility	EN 55024: 2010	EN 61000-4-6: 2009	N/A	
Power-frequency Magnetic Field	EN 55024: 2010	EN61000-4-8: 2010	N/A	
Dips/Voltage Interruption Variation	EN 55024: 2010	EN 61000-4-11: 2004	N/A	

Note: N/A-Not applicable

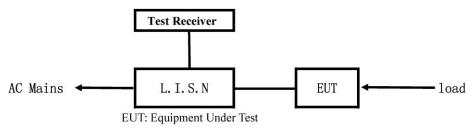
Date: 2015-03-10



#### 4.0 Electromagnetic Interference Test results

#### 4.1 Power line Conducted Emission Test

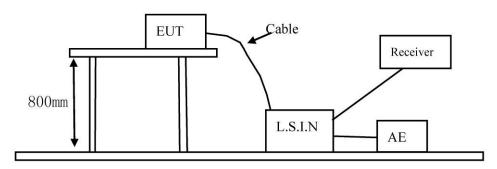
#### 4.1.1 Schematics of the test



#### 4.1.2 Test Method:

The test was performed in accordance with EN 55022: 2010+AC:2011

#### **Block diagram of Test setup**



### 4.1.3 Power line conducted Emission Limit

	Limits dB( µ V)					
Frequency(MHz)	Class A Equipment		Class B Equipment			
	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level		
$0.15 \sim 0.50$	79.0	66.0	66.0~56.0*	56.0~46.0*		
$0.50 \sim 5.00$	73.0	60.0	56.0	46.0		
5.00 ~ 30.00	73.0	60.0	60.0	50.0		

Notes:

- 1. \*decreasing linearly with logarithm of frequency.
- 2. The lower limit shall apply at the transition frequencies

#### 4.1.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

#### Remark:

Calculated measurement uncertainty=3.6dB

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 13 of 52

#### A: Conducted Emission on Live Terminal (150kHz to 30MHz)

**EUT Operating Environment** 

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 KPa

**EUT set Condition:** 

**Equipment Level: Class B** 

Results: N/A

Date: 2015-03-10

Please refer to following diagram for individual

Report No: EMC1503061 Page 14 of 52

B: Conducted Emission on Neutral Terminal (150kHz to 30MHz)

**EUT Operating Environment** 

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 KPa

**EUT set Condition:** 

**Equipment Level: Class B** 

Results: N/A

Date: 2015-03-10

Please refer to following diagram for individual

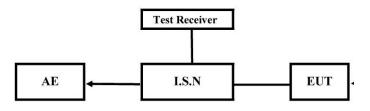
Note: EUT powered by battery, this test item not applicable.

Date: 2015-03-10



#### 4.2 Telecommunication ports Conducted Emission Test

#### 4.2.1 Schematics of the test

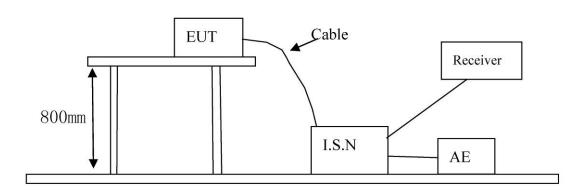


EUT: Equipment Under Test

#### 4.2.2 Test Method:

The test was performed in accordance with EN 55022: 2010+AC:2011

#### **Block diagram of Test setup**



#### 4.2.3 Telecommunication ports conducted Emission Limit

		Class A Limits			Class B Limits			
Frequency(MHz)	Quasi-pe	eak Level	Averag	e Level	Quasi-pea	ık Level	Averag	e Level
	Vlotage	Current	Vlotage	Current	Vlotage	Current	Vlotage	Current
	dB(uV)	dB(uA)	dB(uV)	dB(uA)	dB(uV)	dB(uA)	dB(uV)	dB(uA)
0.15 ~ 0.50	97 to 87	53 to43	84 to74	40 to 30	84 to 74	40 to30	74 to64	30 to 20
$0.50 \sim 30.00$	87	43	74	30	74	30	64	20

Notes:

- 1. \*decreasing linearly with logarithm of frequency.
- 2. The tighter limit shall apply at the transition frequencies

# 4.2.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

#### Remark:

Calculated measurement uncertainty=1.9dB

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 16 of 52

Date: 2015-03-10



## A: Conducted Emission on Telecommunication port (150kHz to 30MHz)

**EUT Operating Environment** 

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Normal operation mode** 

**Equipment Level: Class B** 

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBµV)		Limit(dBµV)	
(MHz)	Tort	Quasi-peak	Average	Quasi-peak	Average
	LAN				
	LAN				

Report No: EMC1503061 Page 17 of 52

Date: 2015-03-10

#### B: Conducted Emission on Telecommunication port (150kHz to 30MHz)

**EUT Operating Environment** 

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 KPa

**EUT set Condition: Normal operation mode** 

**Equipment Level: ClassB** 

Results: N/A

Please refer to following diagram for individual

Frequency	Dort	Port Reading(dBμA)		Limit(dBµA)	
(MHz)	Port	Quasi-peak	Average	Quasi-peak	Average
	LAN				

Note: No such port, this test item not applicable.

Page 18 of 52

Report No: EMC1503061

Date: 2015-03-10



#### 4.3 Radiated Disturbance Test

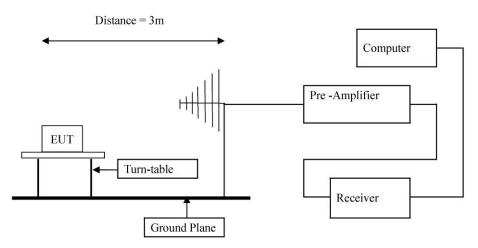
#### 4.3.1 Schematics of the test



#### 4.3.2 Test Method:

The test was performed in accordance with EN 55022: 2010+AC:2011

## **Block diagram of Test setup**



# 4.3.3 Radiated Disturbance Test Limit

Frequency Range (MHz)	Quasi-Peak limits (dB µ V/m)	
	Class A Limits	Class B Limits
30-230	50.00	40.00
230-1000	57.00	47.00

Note: The lower limit shall apply at the transition frequencies

#### 4.3.4 Test result

Limits for Radiated Disturbance test, Please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

#### Remark:

Calculated measurement uncertainty=4.7dB

Date: 2015-03-10



#### A: Radiated Disturbance (30MHz----1000MHz)

# **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

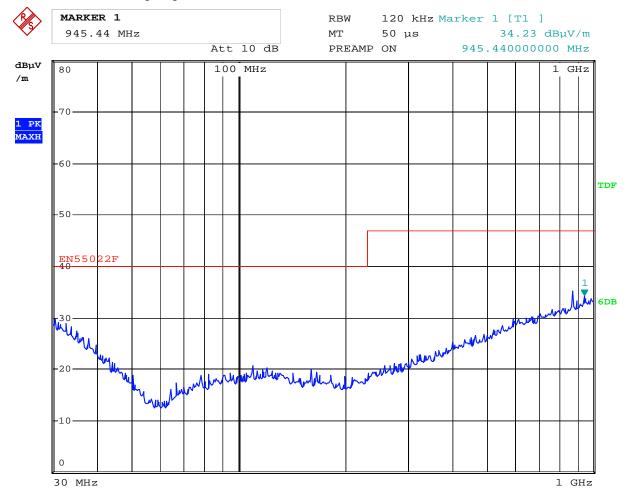
**EUT set Condition: Normal Operation** 

Model: CG-503

**Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.MAR.2015 12:00:31

Frequency (MHz)	Level@3m (dBµV/m)	Antenna Polarity	Limit@3m ( $dB\mu V/m$ )
945.440	34.23	Н	47.00

Date: 2015-03-10



#### **B:** Radiated Disturbance (30MHz----1000MHz)

## **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

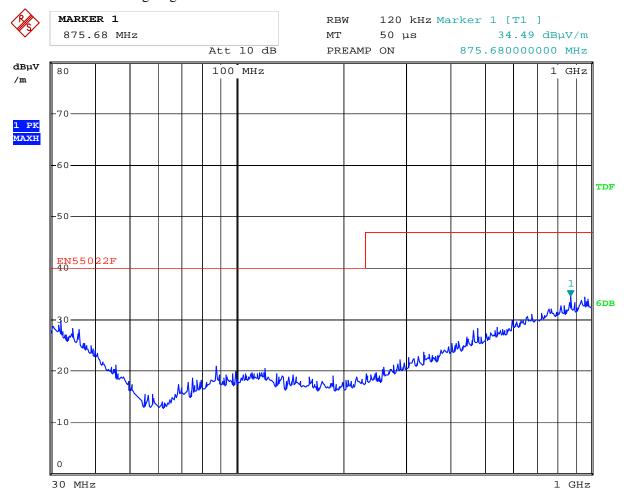
**EUT set Condition: Normal Operation** 

Model: CG-503

**Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.MAR.2015 11:56:08

Frequency (MHz)	Level@3m ( $dB\mu V/m$ )	Antenna Polarity	Limit@3m ( $dB\mu V/m$ )
875.680	34.49	V	47.00

Date: 2015-03-10



#### C: Radiated Disturbance (30MHz----1000MHz)

## **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

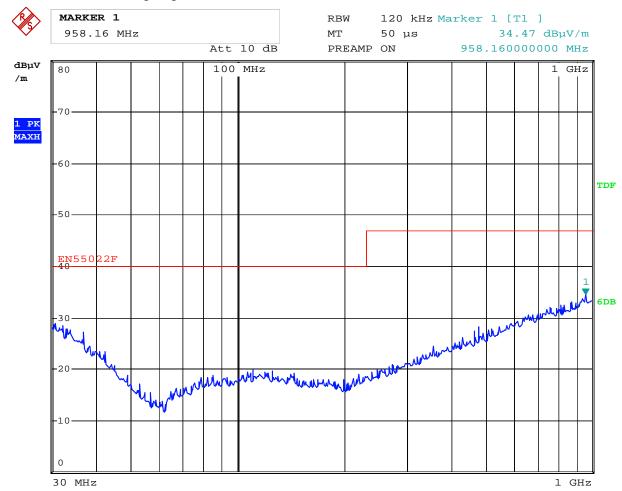
**EUT set Condition: Normal Operation** 

Model: CM-192

**Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.MAR.2015 11:52:27

Frequency (MHz) Level@3m (dBµV/m)		Antenna Polarity	Limit@3m ( $dB\mu V/m$ )
958.160	34.47	Н	47.00

Date: 2015-03-10



#### D: Radiated Disturbance (30MHz----1000MHz)

# **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

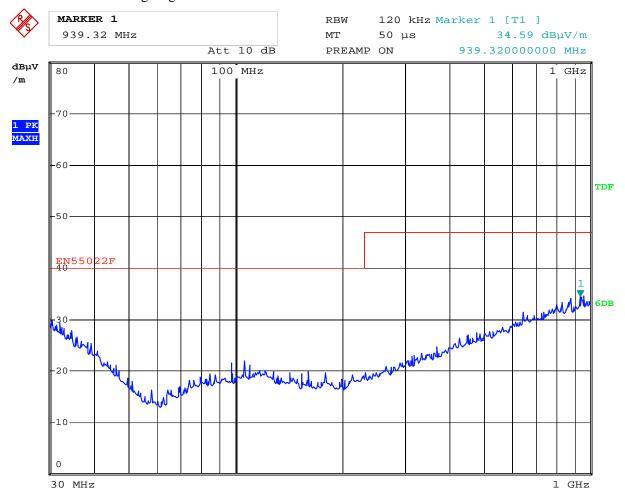
**EUT set Condition: Normal Operation** 

Model: CM-192

**Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.MAR.2015 11:54:29

Frequency (MHz) Level@3m (dB\u03m\)		Antenna Polarity	Limit@3m (dBµV/m)	
939.320	34.59	V	47.00	

Date: 2015-03-10



## E: Radiated Disturbance (30MHz----1000MHz)

## **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

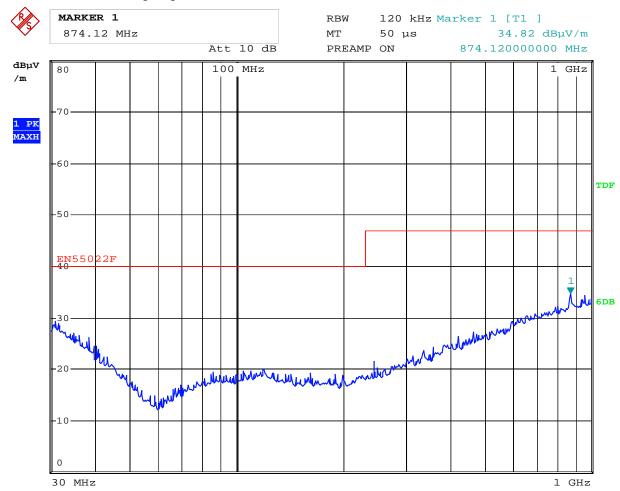
**EUT set Condition: Normal Operation** 

Model: CM-220

**Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.MAR.2015 11:50:23

Frequency (MHz) Level@3m (dBµV/m)		Antenna Polarity	$Limit@3m (dB\mu V/m)$	
874.120	34.82	Н	47.00	

Date: 2015-03-10



#### F: Radiated Disturbance (30MHz----1000MHz)

# **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

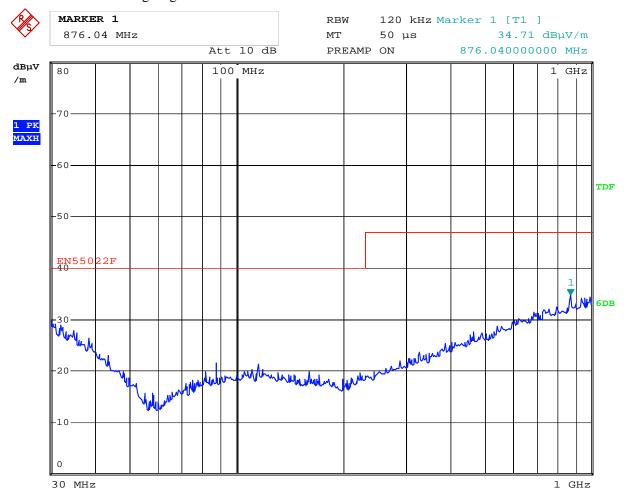
**EUT set Condition: Normal Operation** 

Model: CM-220

**Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.MAR.2015 11:48:12

Frequency (MHz) Level@3m (dBµV/m)		Antenna Polarity	Limit@3m (dBµV/m)	
876.040	34.71	V	47.00	

Date: 2015-03-10



## G: Radiated Disturbance (30MHz----1000MHz)

## **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

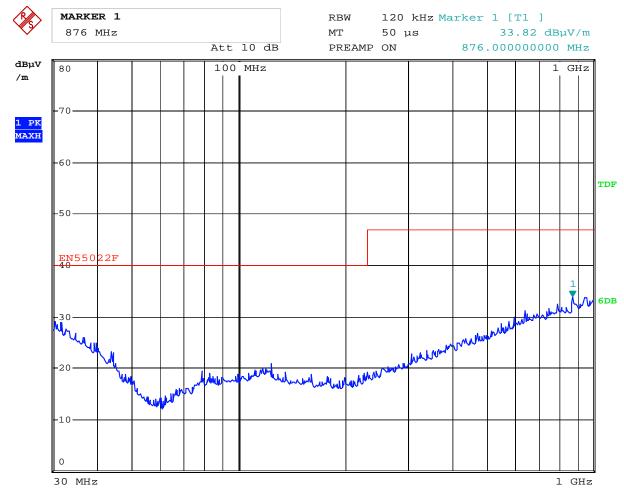
**EUT set Condition: Normal Operation** 

Model: CM-222

**Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.MAR.2015 11:44:45

Frequency (MHz) Level@3m (dBµV/m)		Antenna Polarity	Limit@3m (dBµV/m)	
876.000	33.82	Н	47.00	

Date: 2015-03-10



#### H: Radiated Disturbance (30MHz----1000MHz)

# **EUT Operating Environment**

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 KPa

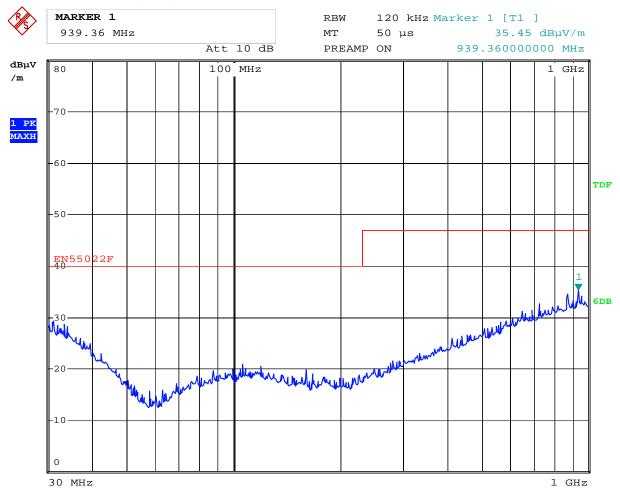
**EUT set Condition: Normal Operation** 

Model: CM-222

**Equipment Level: Class B** 

**Results: Pass** 

Please refer to following diagram for individual



Date: 7.MAR.2015 11:46:41

Frequency (MHz) Level@3m (dB\u03m\)		Antenna Polarity	Limit@3m (dBµV/m)	
939.360	35.45	V	47.00	

Page 27 of 52

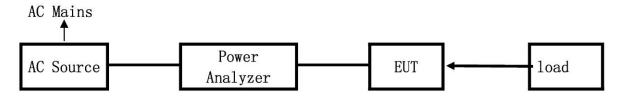
Report No: EMC1503061

Date: 2015-03-10



#### 4.4 Harmonic Current Emission Test

#### 4.4.1 Schematic of the test



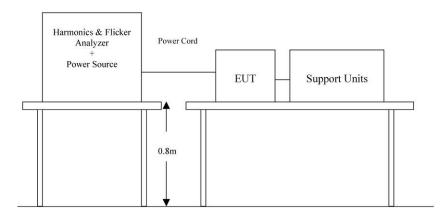
**EUT: Equipment Under Test** 

#### 4.4.2 Test Method:

The test was performed in accordance with EN61000-3-2:2006+A1:2009+A2:2009

\*: The Level of the product is : CLASS D

## **Block diagram of Test setup**



#### 4.4.3 Limits of Harmonic Current Emission For Class A

Harmonic order	Maximum permissible harmonic current
n	A
Odd har	monics
3	2,30
5	1,14
7	0,77
9	0,40
11	0,33
13	0,21
15 ≤ n ≤ 39	0,15 <u>15</u>
Even har	monics
2	1,08
4	0,43
6	0,30
$8 \le n \le 40$	0,23 <u>8</u>

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 28 of 52

Date: 2015-03-10



#### 4.4.4 Test Results

Please refer to the following pages

**Harmonic Current Emission Test** 

**EUT Operating Environment** 

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

**EUT set Condition:** 

Results: N/A

Please refer to following diagram for individual

Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit)%		result/Limit)%		result/Limit)%		result/Limit)%
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

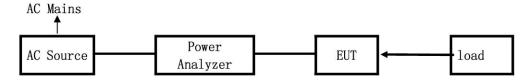
Report No: EMC1503061 Page 29 of 52

Date: 2015-03-10



# 4.5 Voltage Fluctuations & Flicker Test

#### 4.5.1 Schematic of the test

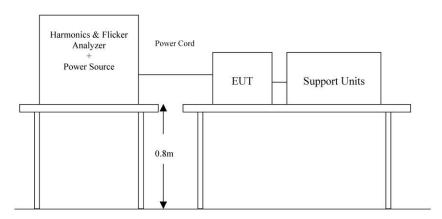


EUT: Equipment Under Test

#### 4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013

## **Block diagram of Test setup**



Report No: EMC1503061 Page 30 of 52

Date: 2015-03-10



#### 4.5.3 Test Results

Result: N/A

Please refer to following diagram for individual

## Maximum Occurring Levels:

Ut: 230.1 (EUT Test RMS Voltage)

Pst:	Limit=	1.0	(The Highest short Term Flicker Value)
Plt:	Limit=	0.65	(The Highest Long Term Flicker Value)
dt(%):	Limit=	3.3%	(The Highest instantaneous Voltage Change (10ms))
dc(%):	Limit=	3.3%	(The highest Relative steady state voltage change (1sec))
dmax:	Limit=	4%	(The highest Max Relative voltage change)
Tdt:	Limit=	500ms	(The Max Time(in milli-sec) that dt exceeds 3%)

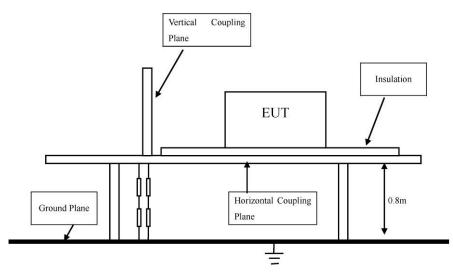
Date: 2015-03-10



## 5.0 Immunity Test

## 5.1 Electrostatic Discharge

#### 5.1.1 Schematic of the test



#### 5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

#### 5.1.3 Test severity

- ±4Kv for direct & in-direct Contact Discharge
- $\pm 8$ Kv for air Discharge

Performance Criterion Require: **B** (Please see following table)

## 5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

# Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (Kv)	discharge(Kv)
1	±2Kv	±2Kv
2	$\pm 4 \mathrm{Kv}$	±4Kv
3	±6Kv	±8Kv
4	±8Kv	±15Kv

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 32 of 52

Date: 2015-03-10



#### 5.1.5 Test Result

#### **EUT Operating Environment**

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

Please refer to the following table for individual results.

<u> </u>			
Location	Discharge Method	Test Voltage	Results
НСР	In-Direct	$\pm 2kV, \pm 4kV$	Pass
VCP	In-Direct	$\pm 2kV, \pm 4kV$	Pass
Screw	Contact Discharge	$\pm 2kV, \pm 4kV$	Pass
Function key	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Gap	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Panel	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Re-set	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass

**Remark:** Calculated measurement uncertainty= 0.2kV

Date: 2015-03-10



#### 5.2 RF field strength susceptibility (80MHz----- 1000MHz)

#### **5.2.1** Schematics of the test



**EUT: Equipment Under Test** 

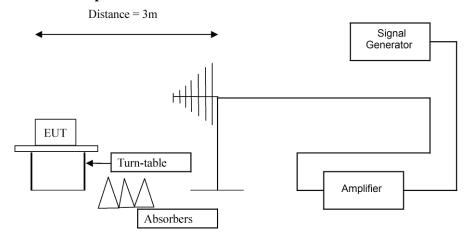
#### 5.2.2 Test Method:

The test was performed in accordance with EN 61000-4-3:2006

Severity: Level 2 (3V/m) Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

#### **Block diagram of Test setup**



# 5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description		
A	A No change in operational mode or degradation of performance outside o specification and no change in stored parameters.		
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.		
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.		

#### **Severity Level**

Level	Field Strength (V/m)
1	1
2	3
3	10

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 34 of 52

Date: 2015-03-10



#### **5.2.4** Test Result:

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following table for individual results.

Frequency	Face	Polarity	Level	Dwell	Sweep	Results
(MHz)			(V/m)	Time(s)	Rate (%)	
80-1000	0°	Horizontal	3	1	1	Pass
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass

Remark: Calculated measurement uncertainty= 80MHz to 1000MHz (+3.7/-1.3) V/m

Date: 2015-03-10



## 5.3 Electrical Fast Transient/Burst (EFT/B) immunity test

#### **5.3.1** Schematics of the test



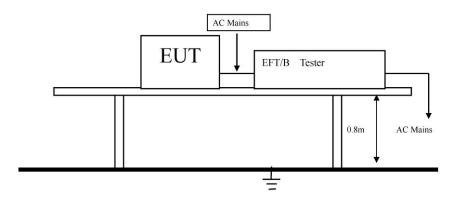
#### 5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2004+A1:2010

Severity: Level 2 (1kV)

Performance Criterion Require: **B** (Please see following table)

## **Block diagram of Test setup**



## 5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description		
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.		
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.		
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.		

#### Severity Level

Open Circuit output Test Voltage $\pm 10\%$			
Level	On power Supply Lines	On I/O (Input/output)	
		Signal data and control lines	
1	0.5kV	0.5kV	
2	1kV	1kV	
3	2kV	2kV	
4	4kV	4kV	
X	Special	Special	

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 36 of 52

Date: 2015-03-10



#### 5.3.4 Test Results

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to following page.

Inject location: AC mains

Inject Line	Voltage kV	Inject Times (s)	Method	Results
L	±1	120	Direct	N/A
N	±1	120	Direct	N/A
L-N	±1	120	Direct	N/A

Report No: EMC1503061 Page 37 of 52

Date: 2015-03-10



### 5.4 Surge test

#### **5.4.1** Schematics of the test



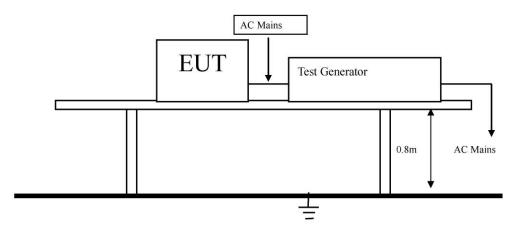
#### **5.4.2** Test Method:

The test was performed in accordance with EN 61000-4-5:2006

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

## **Block diagram of Test setup**



### 5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description		
A No change in operational mode or degradation of performance outside of specification and no change in stored parameters.			
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.		
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.		

Report No: EMC1503061 Page 38 of 52

Date: 2015-03-10



## Severity Level

Severity Level	Open-Circuit Test Voltage	
	kV	
1	0.5	
2	1.0	
3	2.0	
4	4.0	
*	Special	

# 5.4.4 Test Results

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to following page.

Test location:

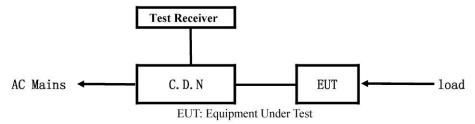
Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
	±	0	5	1.0	N/A
L-N	±	90	5	1.0	N/A
L-IN	±	180	5	1.0	N/A
	<u>+</u>	270	5	1.0	N/A

Date: 2015-03-10



## 5.5 Conducted Immunity test

#### 5.5.1 Schematics of the test



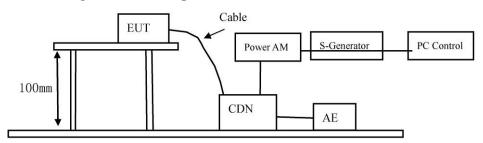
### 5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2009

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

## **Block diagram of Test setup**



# 5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Criterion Description		
A No change in operational mode or degradation of performance outside of specification and no change in stored parameters.			
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.		
C Loss of function allowed during the test, provided that function recoverable or can be recovered by operation of controls.			

# Severity Level

Severity Level	Voltage Level (e.m.f) V
1	1
2	3
3	10
*	Special

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 40 of 52

Date: 2015-03-10



### 5.5.4 Test Results:

### **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

Frequency Range (MHz)	Injected Position	Strength	Criterion	Observation	Result
0.15 - 20	AC Line	3V (rms) Unmodulated	A	A	N/A
20 - 80	AC Line	3V (rms) Unmodulated	A	A	N/A

Date: 2015-03-10



## 5.6 Power-Frequency magnetic field test

#### **5.6.1** Schematics of the test



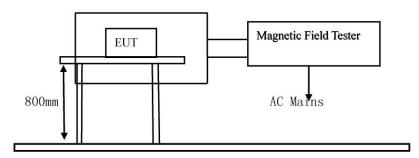
#### 5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

## **Block diagram of Test setup**



### 5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Criterion Description		
A No change in operational mode or degradation of performance outside specification and no change in stored parameters.			
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.		
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.		

### Severity Level

Severity Level	Magnetic Field Strength A/m		
1	1		
2	3		
3	10		
4	30		
5	100		
*	Special		

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Report No: EMC1503061 Page 42 of 52

Date: 2015-03-10



### 5.6.4 Test Results:

## **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

-					
	Test Level	Testing Duration	Coil Orientation	Criterion	Result
	1A/m	5 Mins	X	A	N/A
	1A/m	5 Mins	Y	A	N/A
	1A/m	5 Mins	Z	A	N/A

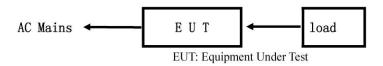
Report No: EMC1503061 Page 43 of 52

Date: 2015-03-10



## 5.7 Voltage Dips/Interruptions immunity test

#### **5.7.1** Schematics of the test

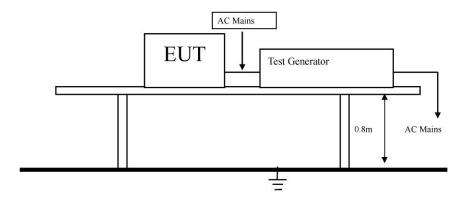


#### 5.7.2 Test Method:

The test was performed in accordance with EN 61000-4-11:2004

Performance Criterion Require: C&B (Please see following table)

## **Block diagram of Test setup**



# 5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Criterion Description		
A No change in operational mode or degradation of performance outside of specification and no change in stored parameters.			
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.		
C Loss of function allowed during the test, provided that function recoverable or can be recovered by operation of controls.			

Report No: EMC1503061 Page 44 of 52

Date: 2015-03-10



## Severity Level

	Test Level %Ut	Reduction	Duration	Performance		
Voltage			(Periods)	Criteria		
Dip	<5	>95	0.5	В		
	70	30	25	С		
	· · · · · · · · · · · · · · · · · · ·					
Voltago	Test Level %Ut	Reduction	Duration	Performance		
Voltage Interceptions			(Periods)	Criteria		
interceptions	<5	>95	250	С		

### **5.7.4** Test Result:

# **EUT Operating Environment**

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following page

Voltage Dip:

Test Level	Reduction	Duration	Phase Angle	Meet	Result
% Ut		(periods)		Criterion	
0	100	0.5	0° -360°	A	N/A
70	30	25	0° - 360°	A	N/A

## Voltage Interceptions:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	250	0° - 360°	В	N/A

Report No: EMC1503061 Page 45 of 52

Date: 2015-03-10



## 6.0 Product Labelling

### 6.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



6.2 Mark Location: Rear enclosure

Page 46 of 52 Report No: EMC1503061

Date: 2015-03-10



## 7.0 Photo of testing



Date: 2015-03-10



### Photo for the EUT



**CG-503** 



CM-192

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Date: 2015-03-10



### Photo for the EUT



**CM-220** 



**CM-222** 

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Date: 2015-03-10



### Photo for the EUT





The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to

adopt any other remedies which may be appropriate.

Date: 2015-03-10



### Photo for the EUT





The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report.

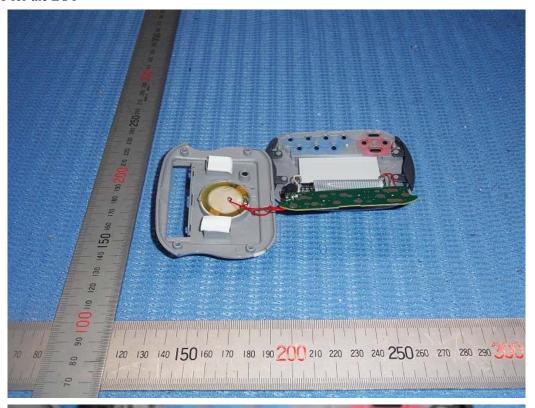
In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES. reserves the rights to withdraw it and to

adopt any other remedies which may be appropriate.

Date: 2015-03-10



## Photo for the EUT





The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any

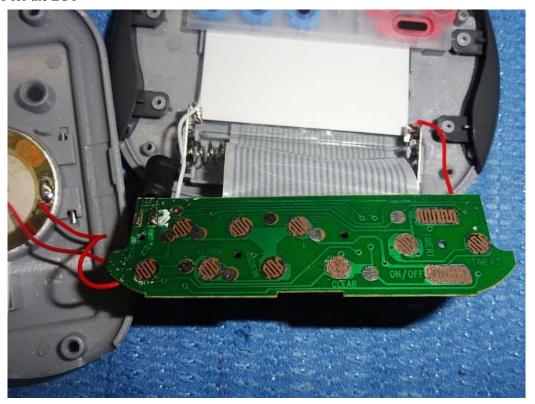
discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES, reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.

Date: 2015-03-10



## Photo for the EUT





## -End of the report-

The report refers only to the sample tested and does not apply to the bulk.

This report is issued in confidence to the client and it will be strictly treated as such by the SHENZHEN TIMEWAY TESTING LABORATORIES. It may not be reproduced rather in its entirety or in part and it may not be used for adverting. The client to whom the report is issued may, however, show or send it . or a certified copy there of prepared by the SHENZHEN TIMEWAY TESTING LABORATORIES. to his customer. Supplier or others persons directly concerned. SHENZHEN TIMEWAY TESTING LABORATORIES. will not, without the consent of the client enter into any

discussion of correspondence with any third party concerning the contents of the report.

In the event of the improper use of the report. The SHENZHEN TIMEWAY TESTING LABORATORIES, reserves the rights to withdraw it and to adopt any other remedies which may be appropriate.